

FIG. 1

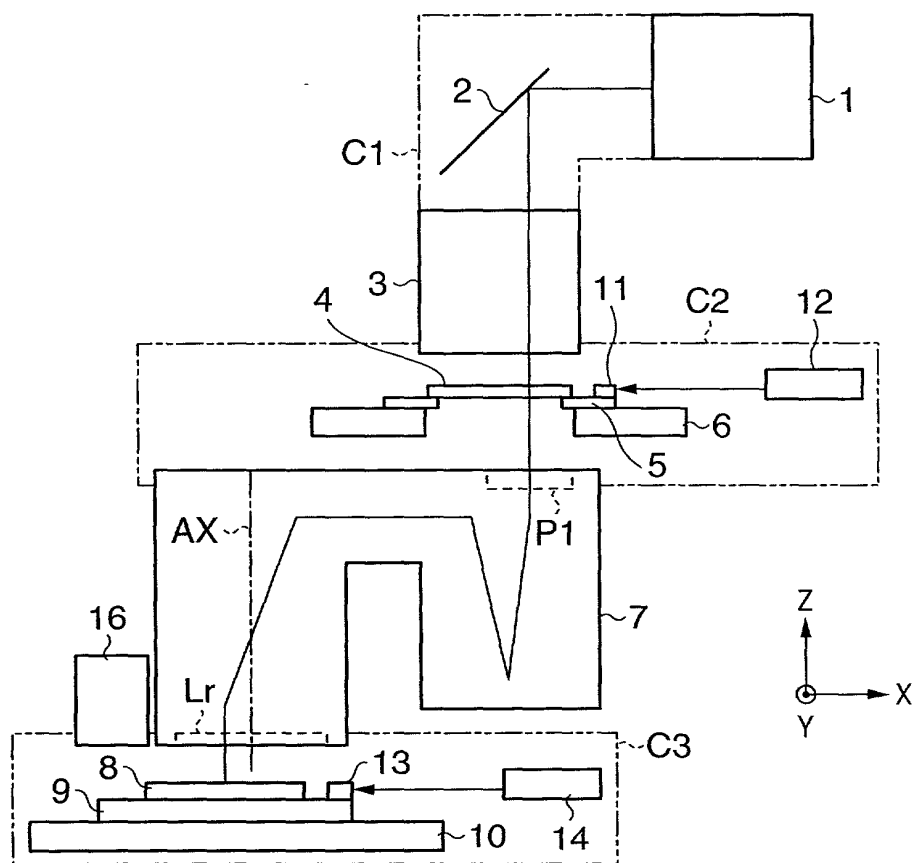


FIG. 2A

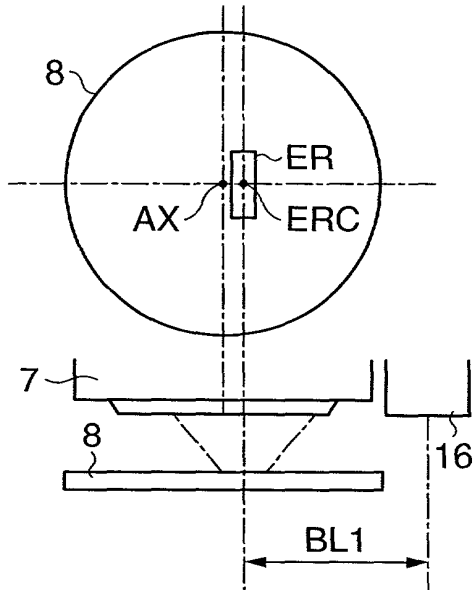


FIG. 2B

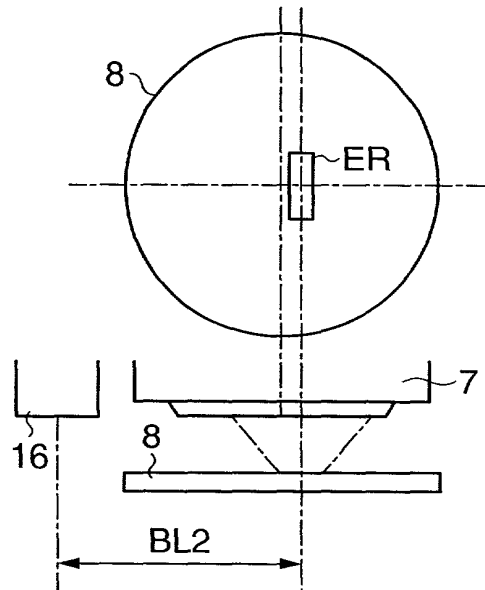


FIG. 3

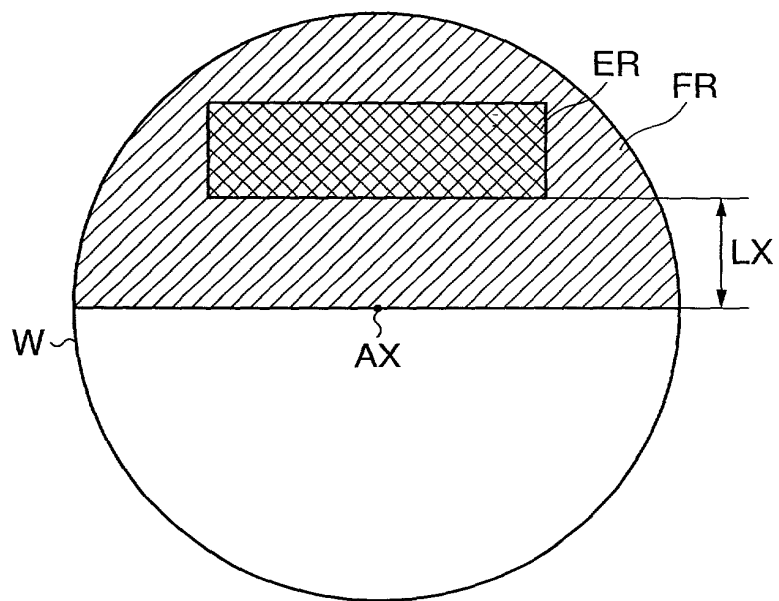


FIG. 4

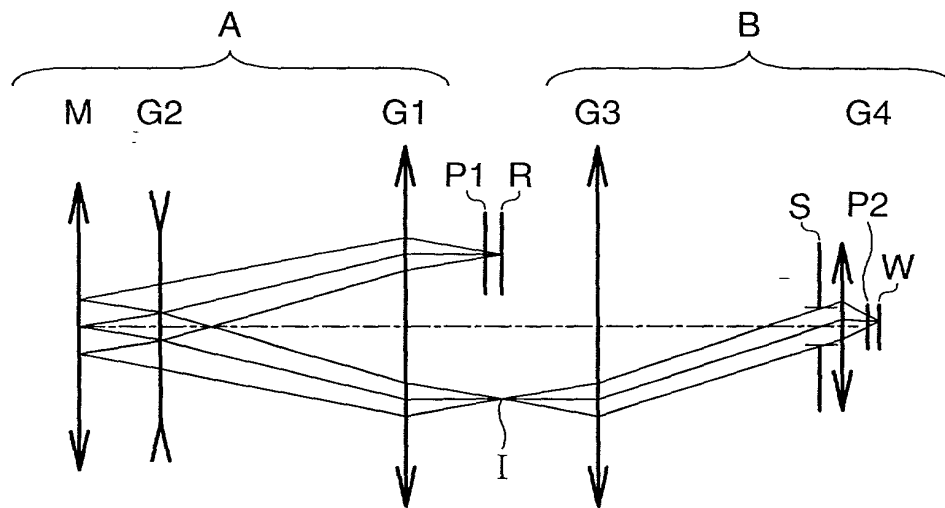


FIG. 5

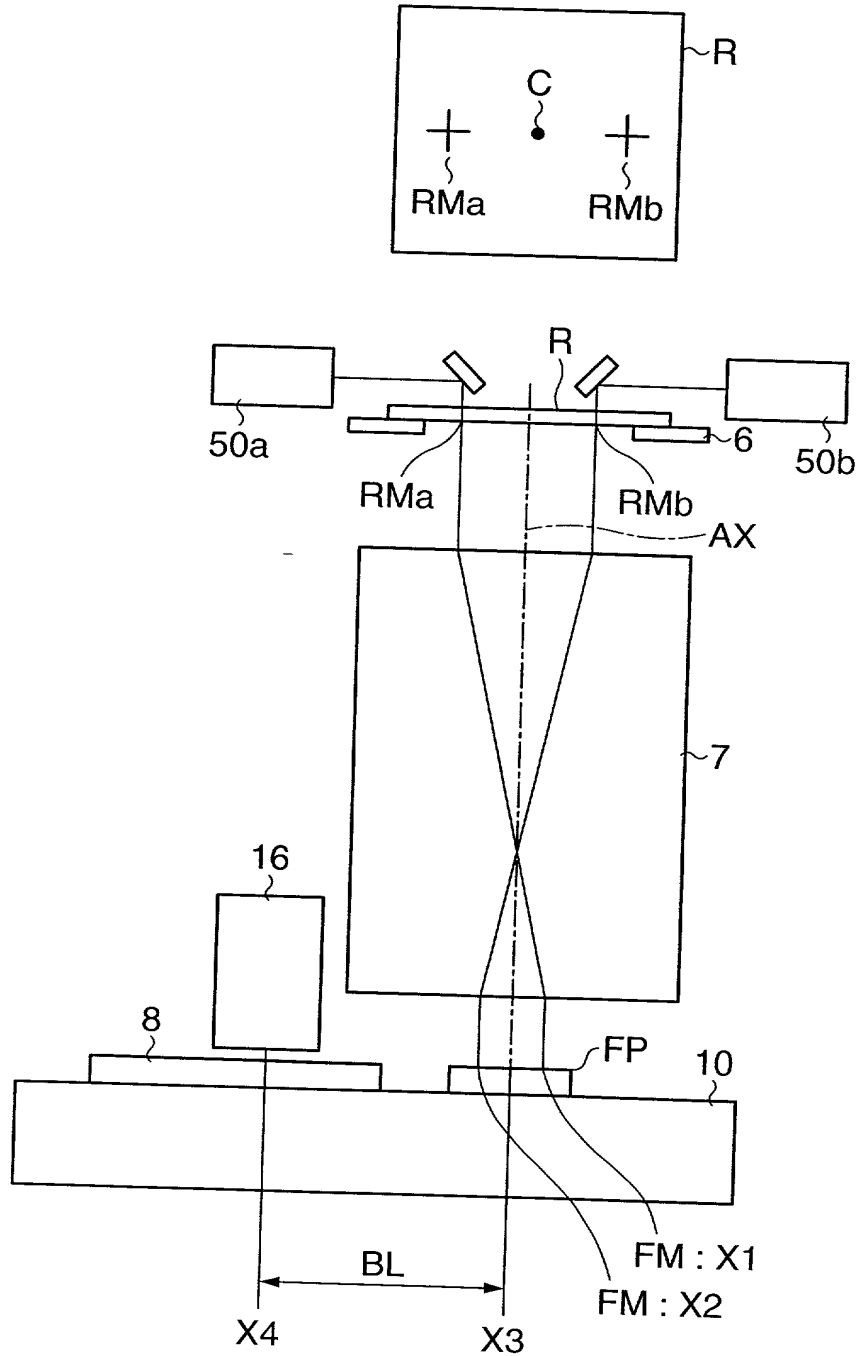


FIG. 6

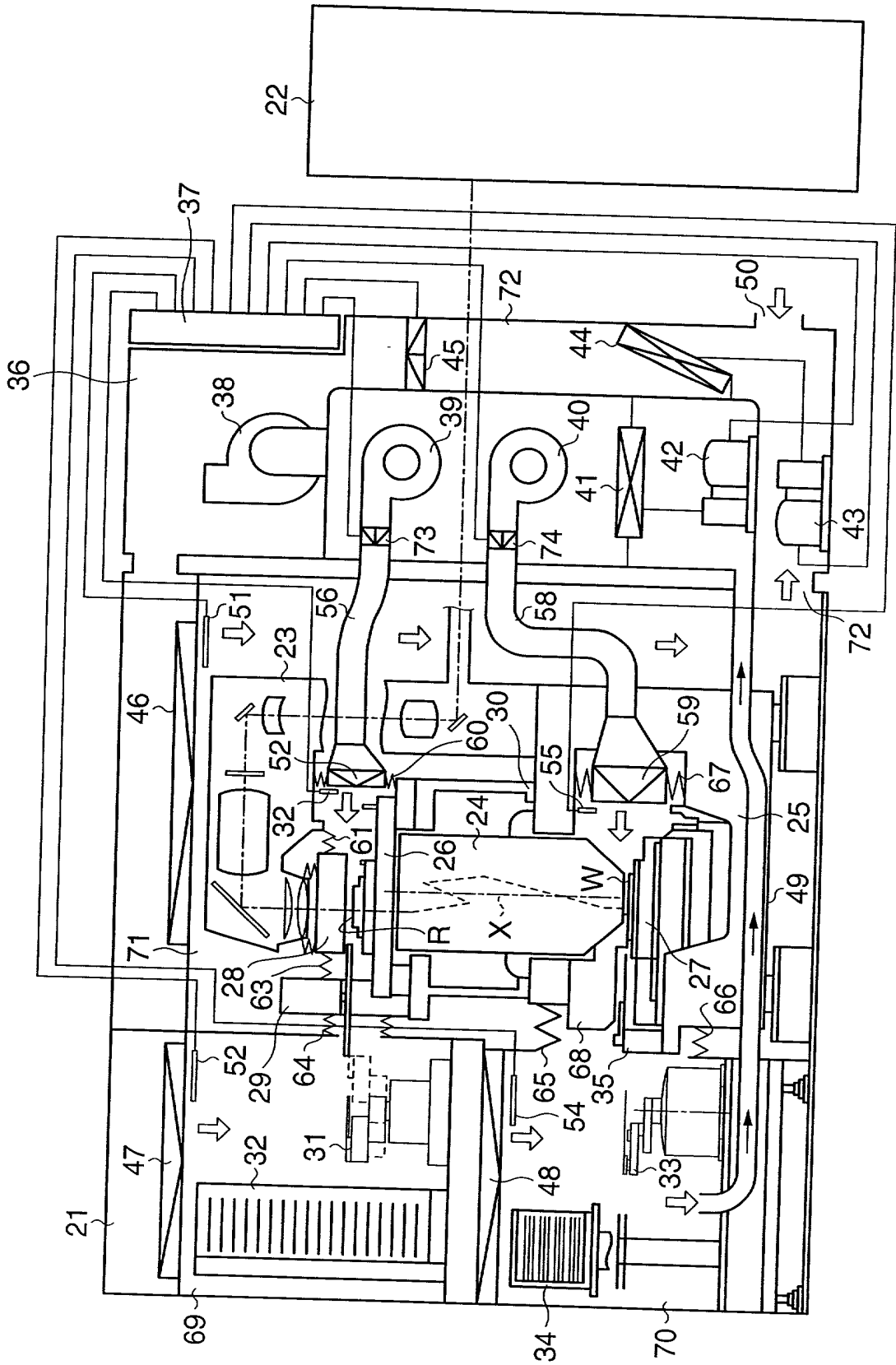


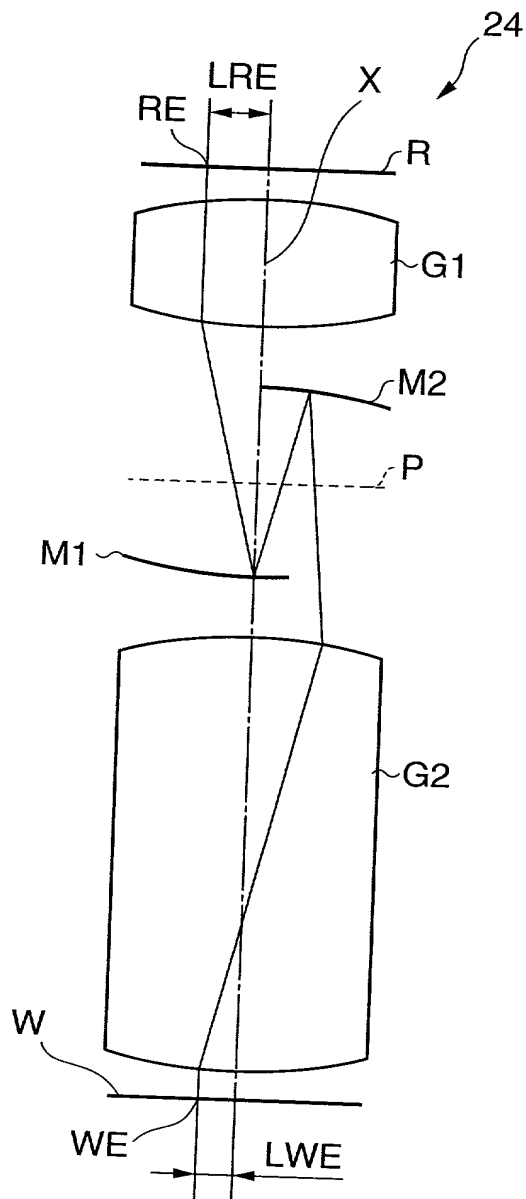
FIG. 7

FIG. 8

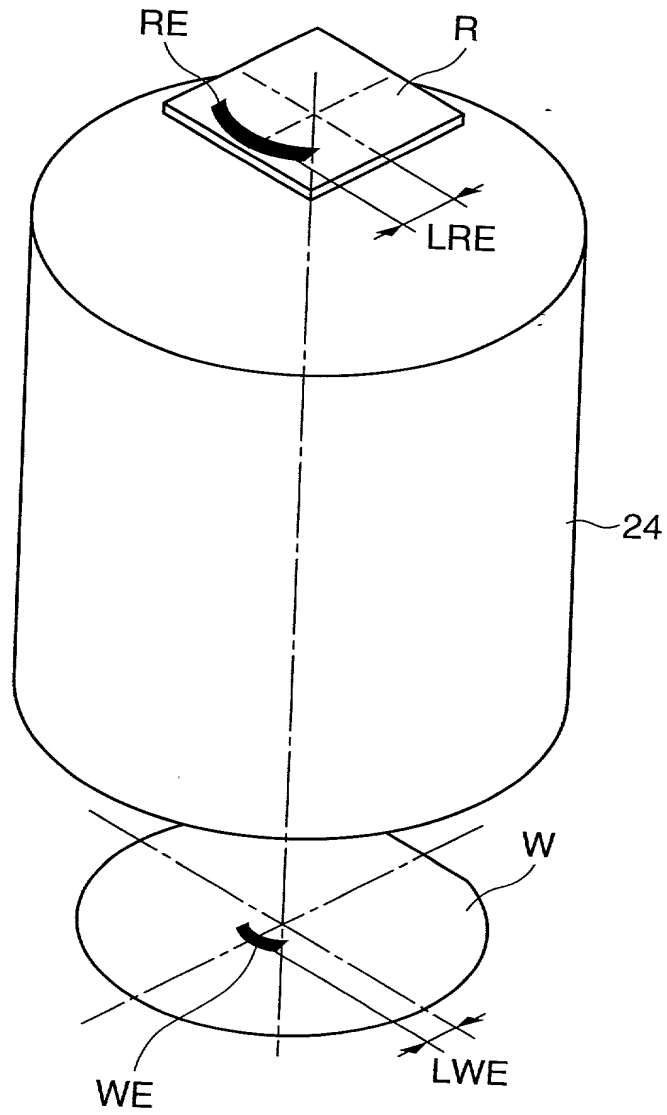


FIG. 9A

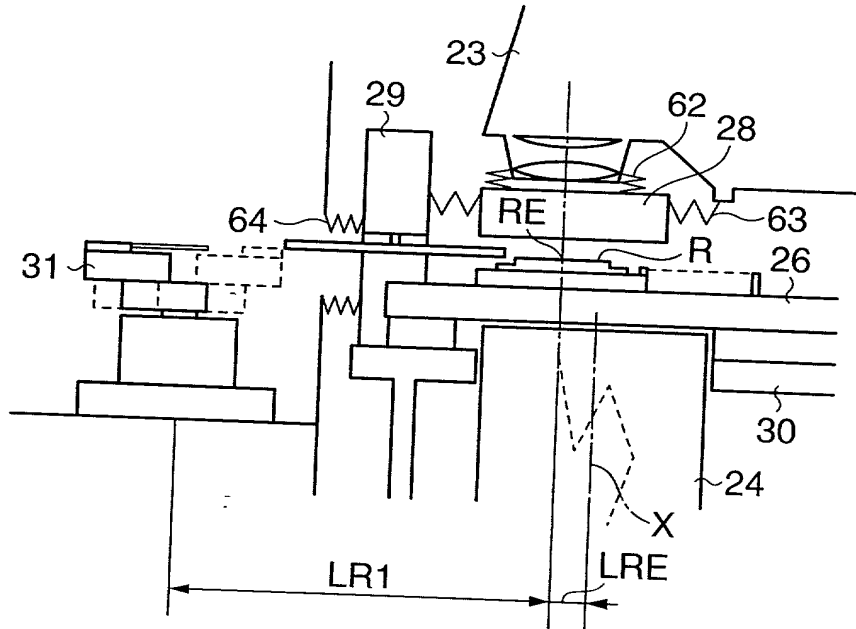


FIG. 9B

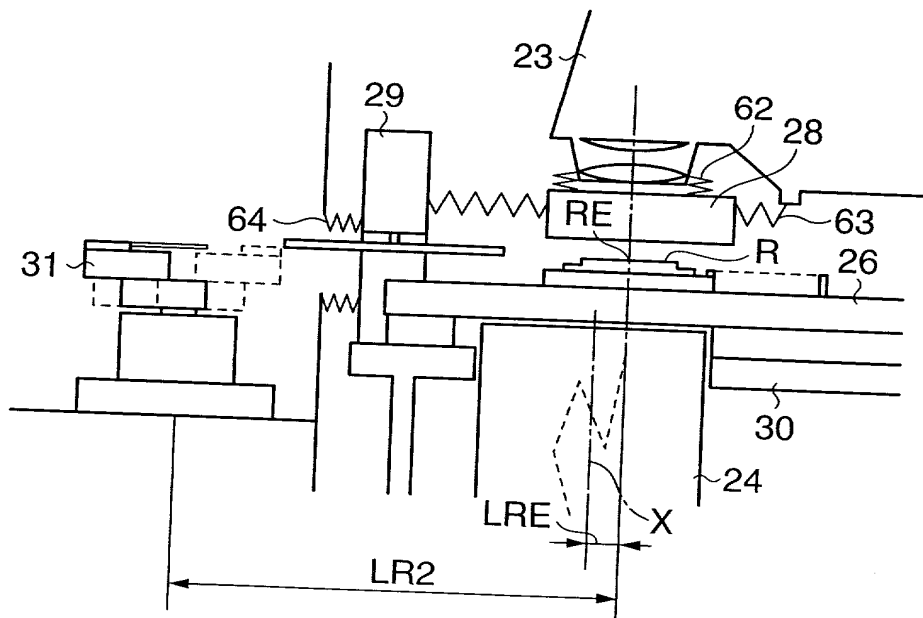


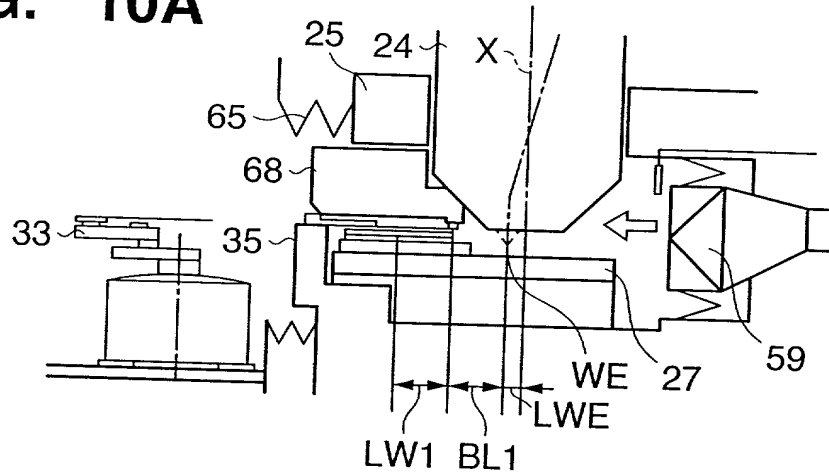
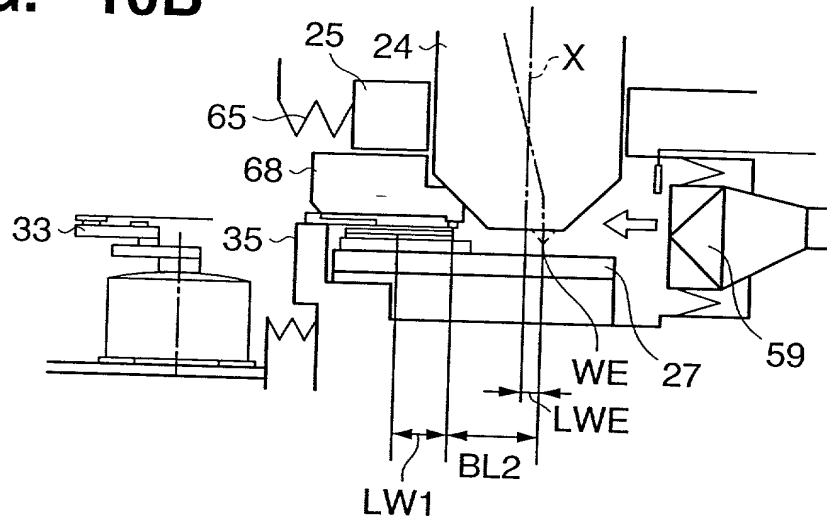
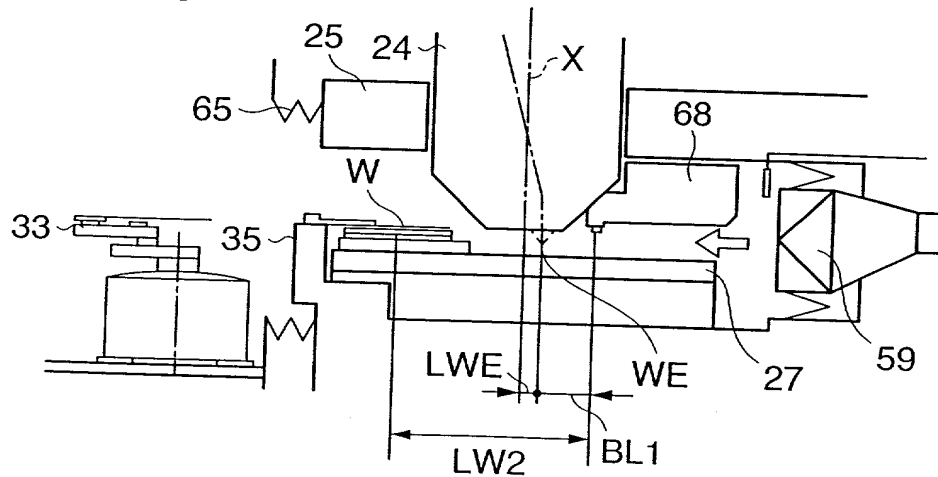
FIG. 10A**FIG. 10B****FIG. 10C**

FIG. 11

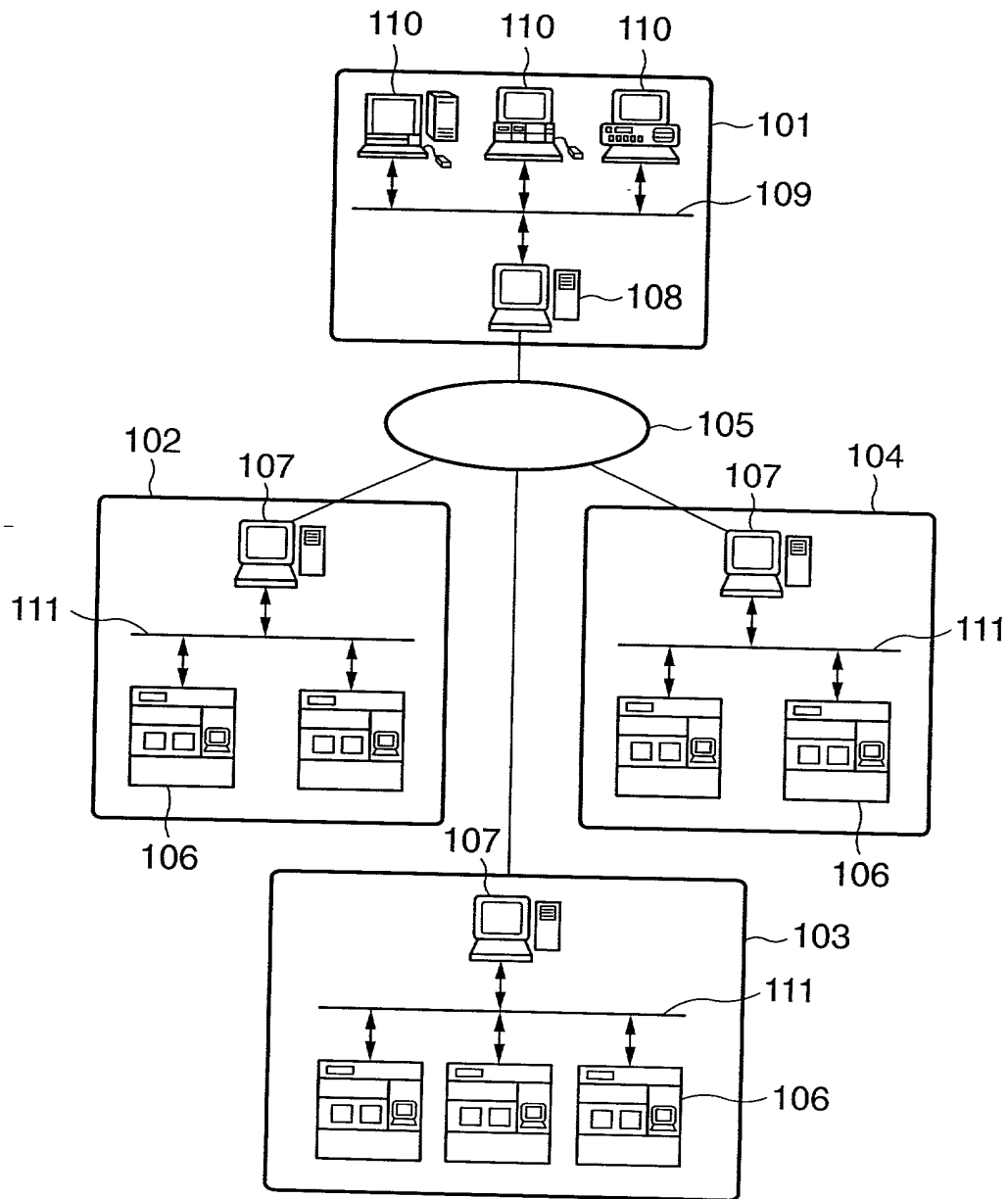


FIG. 12

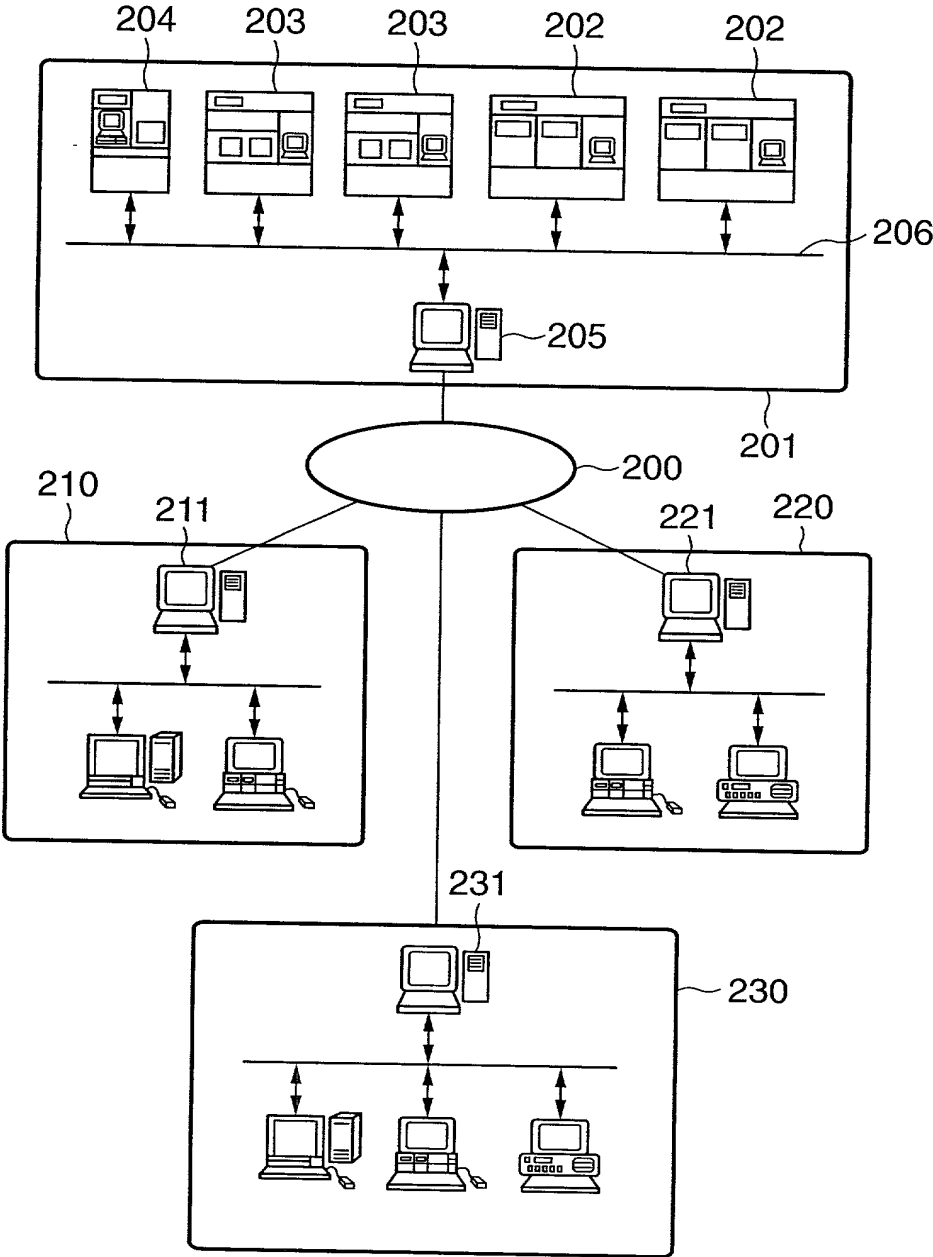


FIG. 13

URL

MALFUNCTION DATABASE INPUT SCREEN

DATE OF OCCURRENCE ~ 404

MODEL ~ 401

SUBJECT MATTER ~ 403

EQUIPMENT SERIAL NO. ~ 402

DEGREE OF URGENCY ~ 405

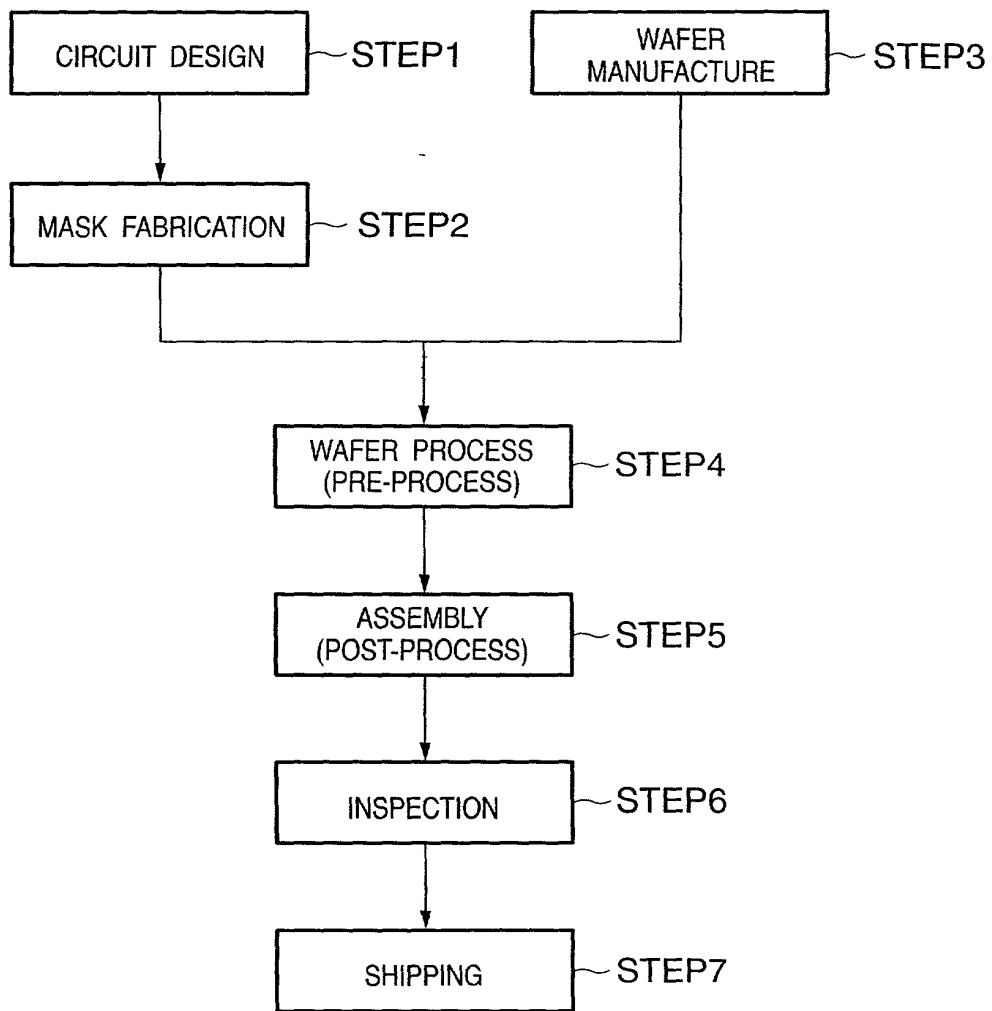
CONDITION ~ 406

COUNTERMEASURE METHOD ~ 407

PROGRESS REPORT ~ 408

~ 410

~ 412

FIG. 14

FLOW OF SEMICONDUCTOR DEVICE MANUFACTURE

FIG. 15